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Applicants: Dr. Uwe W. Hamm,

Examiner:

Serial No:

Group Art Unit:

Filed:

December 6, 2001

Date: D

December 6, 2001

For: PROCESS AND DEVICE FOR IN-SITU DECONTAMINATION OF AN

EUV-LITHOGRAPHY DEVICE

Assistant Commissioner for Patents Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Please amend the application as indicated below before calculation of the application fees as follows:

IN THE SPECIFICATION:

Page 1:

Please replace the first paragraph as follows:

FIELD OF THE INVENTION

The invention concerns a process as well as a device for in-situ decontámination of an EUV lithography device.

Please replace the second paragraph on Page 1 as follows:

BACKGROUND OF THE INVENTION

EUV lithography devices are used in the manufacturing of semiconductor components, e.g. integrated circuits. Lithography devices, which are operated in the wavelength range of extreme ultraviolet (e.g. at a